

Notice of References Cited	Application/Control No. 10/826,571	Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,746,879	07-1973	Esaki et al.	359/328
*	B	US-5,062,112	10-1991	Buchman et al.	372/3
*	C	US-5,436,757	07-1995	Okazaki et al.	359/332
*	D	US-6,154,310	11-2000	Galvanauskas et al.	359/328
*	E	US-6,496,634	12-2002	Levenson, Marc David	385/125
*	F	US-6,924,924	08-2005	Fujiwara et al.	359/326
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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